

FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE INFORMATION DISCLOSURE STATEMENT BY APPLICANT (USE SEVERAL SHEETS IF NECESSARY)	ATTY. DOCKET NO. MNDSPD.00278	APPLICATION NO. 10/810,789
	APPLICANT Mark Lynch	
	FILING DATE March 26, 2004	GROUP 2829

U.S. PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	NAME	CLASS	SUBCLASS	FILING DATE (IF APPROPRIATE)

FOREIGN PATENT DOCUMENTS

EXAMINER INITIAL	DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUBCLASS	TRANSLATION	
						YES	NO

OTHER DOCUMENTS (INCLUDING AUTHOR, TITLE, DATE, PERTINENT PAGES, ETC.)

EXAMINER INITIAL	
PP	FlipChips Dot Com "Tutorial 2 - Solder Bump Flip Chip", http://www.flipchips.com/tutorial102a.html , 7 pages "Highly Accelerated Stress Test (HAST)", © 1991-2001 Innovative Circuits Engineering, Inc., 1 page
PP	"HAST (Highly Accelerated Stress Testing)", © 2003 Environ Laboratoies, Inc., 2 pages "What is HAST?-- Introduction", © 2003, ESPEC NORTH AMERICA, INC., 2 pages
PP	"What is HAST?-- Principles of High Humidity", © 2003, ESPEC NORTH AMERICA, INC., 2 pages "What is HAST?-- Test Equipment", © 2003, ESPEC NORTH AMERICA, INC., 6 pages
PP	"What is HAST? -- Testing Techniques", © 2003, ESPEC NORTH AMERICA, INC., 2 pages "What is HAST?-- Reliability Analysis", © 2003, ESPEC NORTH AMERICA, INC., 2 pages

EXAMINER /Paresh Patel/	DATE CONSIDERED 10/15/2006
*EXAMINER: INITIAL IF CITATION CONSIDERED, WHETHER OR NOT CITATION IS IN CONFORMANCE WITH MPEP 609; DRAW LINE THROUGH CITATION IF NOT IN CONFORMANCE AND NOT CONSIDERED, INCLUDE COPY OF THIS FORM WITH NEXT COMMUNICATION TO APPLICANT.	